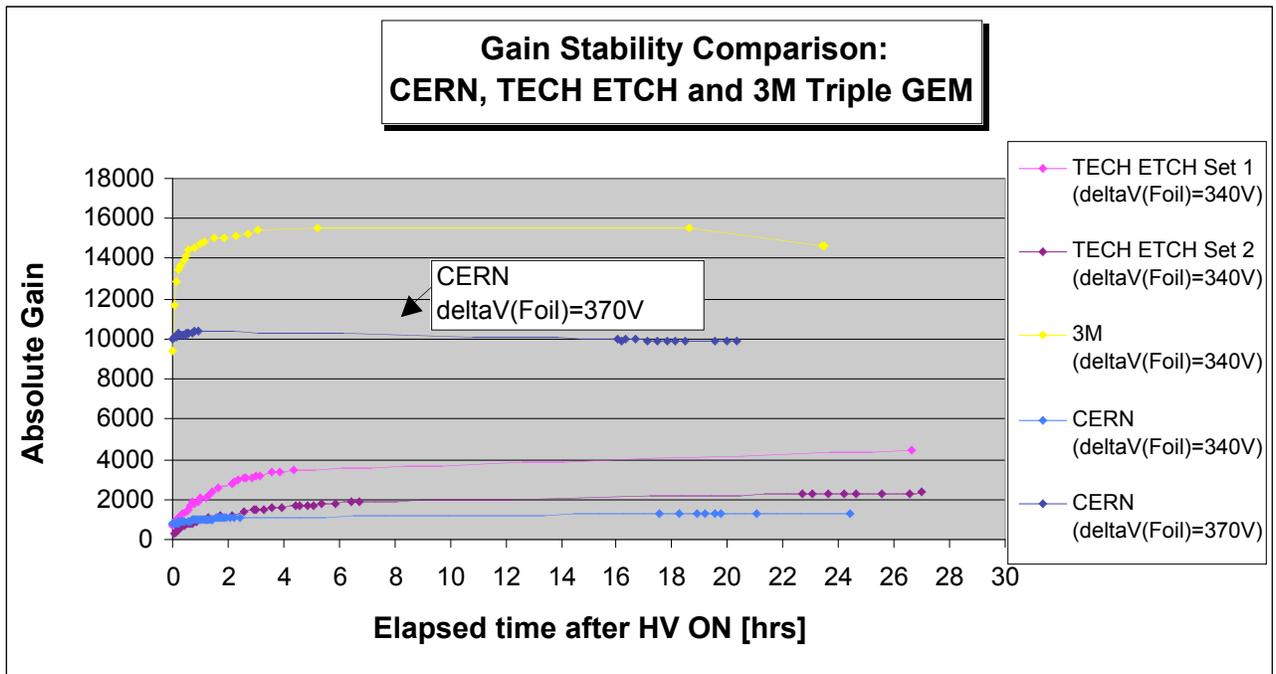
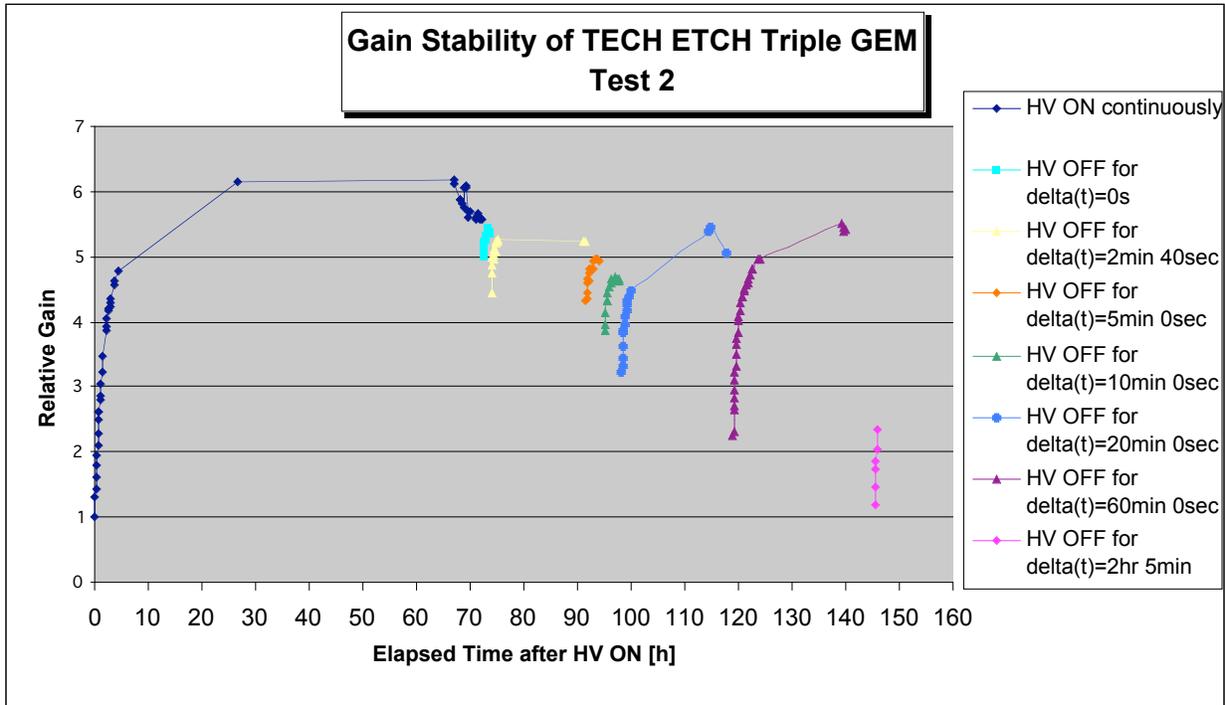


**Figure 1: Absolute Gain Vs. Foil Potential: potential across all three foils are equal, and field within gaps are invariant.**



**Figure 2: Absolute Gain Vs. Elapsed Time after HV ON.**



**Figure 3: Relative Gain Vs. Elapsed Time after HV ON, but power was intentionally interrupted for various periods of time to observe the affects of discharging. The 3M foils exhibit similar behavior.**

Throughout the course of each measurement, none of the GEM foils ever tripped even after 5-7 days of continual operation, and each maintained sub-nA leakage currents. As commonly observed behavior, the gain was observed to fluctuate roughly on the order of +/- 10% after the GEM had already stabilized, for all three sets of foils tested.

<i>Manufacturer</i>	<b>CERN</b>	<b>3M</b>	<b>Tech Etch</b>
<b>FWHM % Resolution</b>	<i>18 - 21%</i>	<i>28 - 32%</i>	<i>24- 26%</i>